### 1. General description

The 74ABT125 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT125 device is a quad buffer that is ideal for driving bus lines. The device features four Output Enables ( $1\overline{OE}$ ,  $2\overline{OE}$ ,  $3\overline{OE}$ ,  $4\overline{OE}$ ), each controlling one of the 3-state outputs.

### 2. Features and benefits

- Quad bus interface
- 3-state buffers
- Live insertion and extraction permitted
- Output capability: HIGH –32 mA; LOW +64 mA
- Power-up 3-state
- Inputs are disabled during 3-state mode
- Latch-up protection exceeds 500 mA per JESD78 class II level A
- ESD protection:
  - HBM JESD22-A114E exceeds 2000 V
  - MM JESD22-A115-A exceeds 200 V

### 3. Ordering information

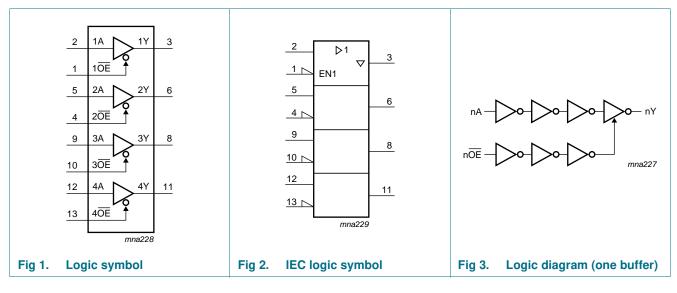
#### Table 1.Ordering information

Type number	Package								
	Temperature range	Name	Description	Version					
74ABT125N	–40 °C to +85 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1					
74ABT125D	–40 °C to +85 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1					
74ABT125DB	–40 °C to +85 °C	SSOP14	plastic shrink small outline package; 14 leads; body width 5.3 mm	SOT337-1					
74ABT125PW	–40 °C to +85 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1					
74ABT125BQ	–40 °C to +85 °C	DHVQFN14	plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body $2.5 \times 3 \times 0.85$ mm	SOT762-1					



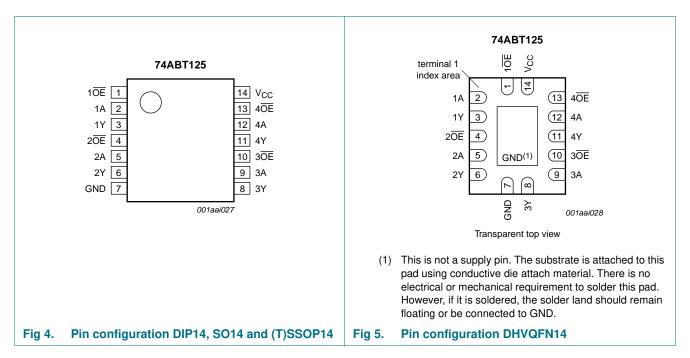
74ABT125 Quad buffer: 3-state

### 4. Functional diagram



### 5. Pinning information

#### 5.1 Pinning



### 5.2 Pin description

Table 2. Pin des	cription	
Symbol	Pin	Description
1OE to 4OE	1, 4, 10, 13	output enable input (active LOW)
1A to 4A	2, 5, 9, 12	data input
1Y to 4Y	3, 6, 8, 11	data output
GND	7	ground (0 V)
V <sub>CC</sub>	14	supply voltage

### 6. Functional description

Table 3.	Function selection <sup>[1]</sup>		
Inputs nOE			Output
nOE		nA	nY
L		L	L
L		Н	Н
Н		Х	Z

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care; Z = high-impedance OFF-state.

### 7. Limiting values

#### Table 4.Limiting values<sup>[1]</sup>

In accordance with the Absolute Maximum Rating System (IEC 60134).

		5, (			
Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		-0.5	+7.0	V
VI	input voltage		-1.2	+7.0	V
Vo	output voltage	output in OFF-state or HIGH-state	-0.5	+5.5	V
l <sub>IK</sub>	input clamping current	V <sub>1</sub> < 0 V	-18	-	mA
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-50	-	mA
lo	output current	output in LOW-state	-	128	mA
Tj	junction temperature		[2] _	150	°C
T <sub>stg</sub>	storage temperature		-65	+150	°C
P <sub>tot</sub>	total power dissipation	$T_{amb} = -40 \ ^{\circ}C \ to \ +85 \ ^{\circ}C$	<u>[3]</u> _	500	mW

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

[3] SO14 packages: above 70 °C P<sub>tot</sub> derate linearly with 8 mW/K
 SSOP14 and TSSOP20 packages: above 60 °C P<sub>tot</sub> derate linearly with 5.5 mW/K
 DHVQFN14 packages: above 60 °C P<sub>tot</sub> derate linearly with 4.5 mW/K

Quad buffer; 3-state

## 8. Recommended operating conditions

#### Table 5. Operating conditions

Voltages are referenced to GND (ground = 0 V).

•					
Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		4.5	5.5	V
VI	input voltage		0	$V_{CC}$	V
V <sub>IH</sub>	HIGH-level input voltage		2.0	-	V
V <sub>IL</sub>	LOW-level Input voltage		-	0.8	V
I <sub>OH</sub>	HIGH-level output current		-32	-	mA
I <sub>OL</sub>	LOW-level output current		-	64	mA
$\Delta t/\Delta V$	input transition rise and fall rate		-	10	ns/V
T <sub>amb</sub>	ambient temperature	in free air	-40	+85	°C

### 9. Static characteristics

#### Table 6. Static characteristics

0.9 – 2.9	<b>Тур</b> –0.9	<b>Max</b> -1.2		<b>Max</b> -1.2	V
2.9	-0.9	-1.2	-	-1.2	V
				••	v
	2.9	-	2.5	-	V
3.4	3.4	-	3.0	-	V
2.4	2.4	-	2.0	-	V
.35 0	0.35	0.55	-	0.55	V
).01 ±	±0.01	±1.0	-	±1.0	μA
5.0 ±	±5.0	±100	-	±100	μA
5.0 ±	±5.0	±50	-	±50	μA
.0 5	1.0	50	-	50	μA
1.0 –	-1.0	-50	-	-50	μA
5.0 t	5.0	50	-	50	μA
100 -	-100	-180	-50	-180	mA
35 2	65	250	-	250	μA
		. –		00	
12 <sup>·</sup>	12	15	-	30	mΑ
1	1 -1 5 -1	.0 1.0 5.0	.0 50 1.0 -50 5.0 50 100 -180 55 250	.0 50 - 1.0 -50 - 5.0 50 - 100 -180 -50 55 250 -	.0       50       -       50         1.0       -50       -       -50         3.0       50       -       50         100       -180       -50       -180         55       250       -       250

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Quad buffer; 3-state

Symbol	Parameter	Conditions		25 °C			–40 °C to +85 °C		Unit
				Min	Тур	Max	Min	Max	
∆I <sub>CC</sub> additional supply current		per control pin; $V_{CC} = 5.5 V$ ; one control input at 3.4 V, other inputs at $V_{CC}$ or GND	<u>[3]</u>						
	outputs enabled		-	0.5	1.5	-	1.5	mA	
	outputs disabled		-	50	250	-	250	mA	
		one enable input at 3.4 V and other inputs at $V_{CC}$ or GND; outputs disabled		-	0.5	1.5	-	1.5	mA
CI	input capacitance	$V_{I} = 0 V \text{ or } V_{CC}$		-	4	-	-	-	pF
Co	output capacitance	outputs disabled; $V_0 = 0 V \text{ or } V_{CC}$		-	7	-	-	-	pF

#### Table 6. Static characteristics ...continued

[1] This parameter is valid for any V<sub>CC</sub> between 0 V and 2.1 V, with a transition time of up to 10 ms. From V<sub>CC</sub> = 2.1 V to V<sub>CC</sub> = 5 V  $\pm$  10 %, a transition time of up to 100  $\mu$ s is permitted.

[2] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[3] This is the increase in supply current for each input at 3.4 V.

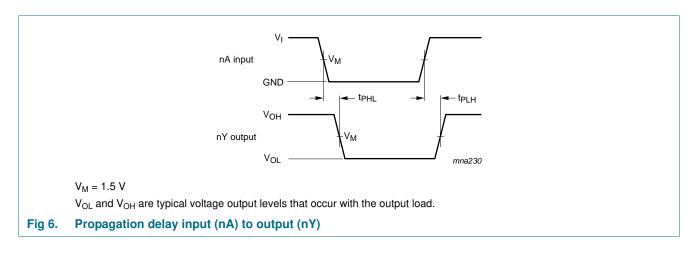
## **10. Dynamic characteristics**

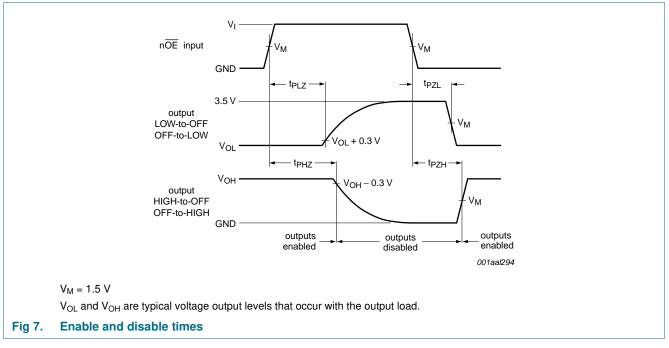
#### Table 7.Dynamic characteristics

GND = 0 V. Test circuit is shown in Figure 8.

Symbol	Parameter	Conditions	25 °C;	25 °C; V <sub>CC</sub> = 5.0 V			–40 °C to +85 °C; V <sub>CC</sub> = 5.0 V ± 0.5 V		
			Min	Тур	Max	Min	Max		
t <sub>PLH</sub>	LOW to HIGH propagation delay	nA to nY, see Figure 6	1.0	2.8	4.1	1.0	4.6	ns	
t <sub>PHL</sub>	HIGH to LOW propagation delay	nA to nY; see <u>Figure 6</u>	1.0	3.1	4.6	1.0	4.9	ns	
t <sub>PZH</sub>	OFF-state to HIGH propagation delay	nOE to nY; see <u>Figure 7</u>	1.0	3.2	5.0	1.0	5.9	ns	
t <sub>PZL</sub>	OFF-state to LOW propagation delay	nOE to nY; see <u>Figure 7</u>	1.0	4.2	6.2	1.0	6.8	ns	
t <sub>PHZ</sub>	HIGH to OFF-state propagation delay	nOE to nY; see <u>Figure 7</u>	1.0	4.1	5.4	1.0	6.2	ns	
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	nOE to nY; see <u>Figure 7</u>	1.5	2.8	5.0	1.5	5.5	ns	

### 11. Waveforms



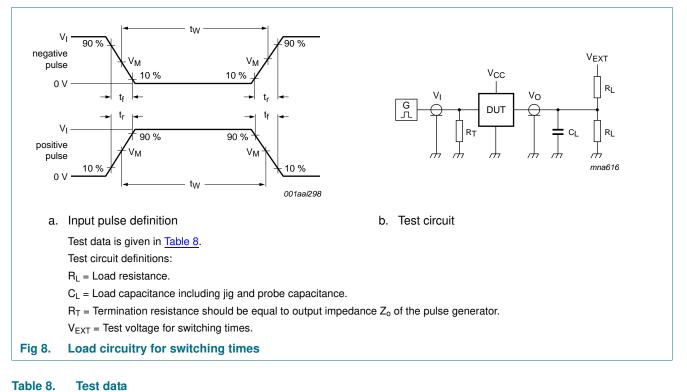


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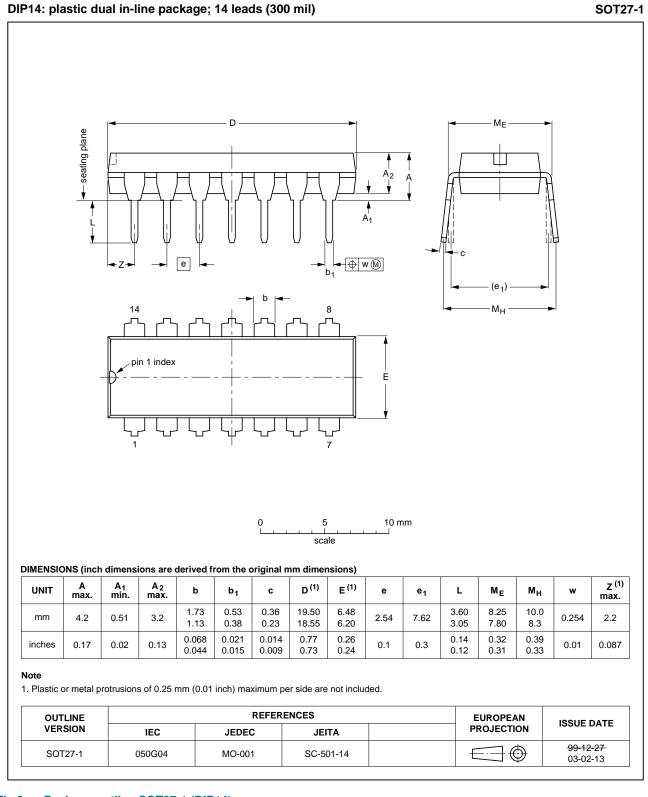
Quad buffer; 3-state



Input			Load		V <sub>EXT</sub>			
Vi	fi	tw	t <sub>r</sub> , t <sub>f</sub>	CL	RL	t <sub>PHL</sub> , t <sub>PLH</sub>	t <sub>PZH</sub> , t <sub>PHZ</sub>	t <sub>PZL</sub> , t <sub>PLZ</sub>
3.0 V	1 MHz	500 ns	≤ 2.5 ns	50 pF	500 Ω	open	open	7.0 V

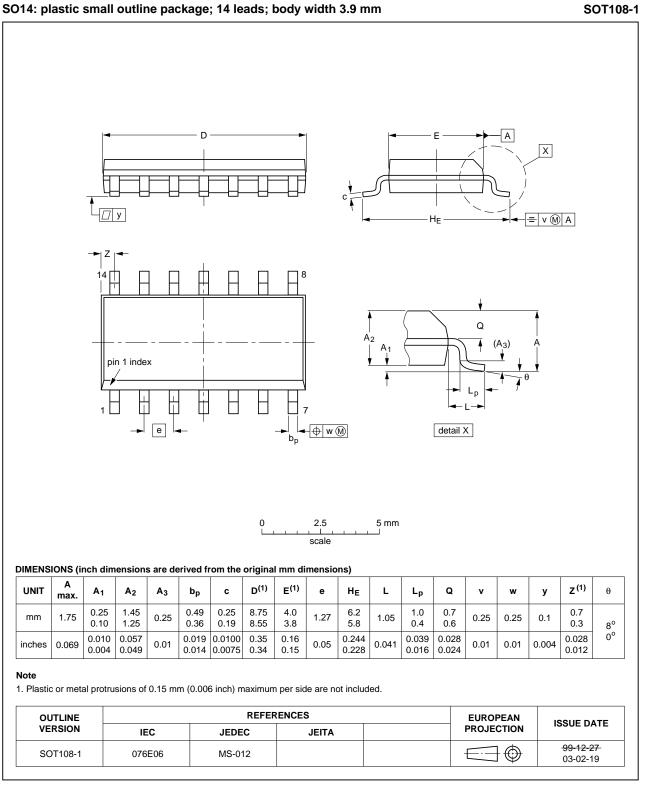
74ABT125 Quad buffer; 3-state

### 12. Package outline



#### Fig 9. Package outline SOT27-1 (DIP14)

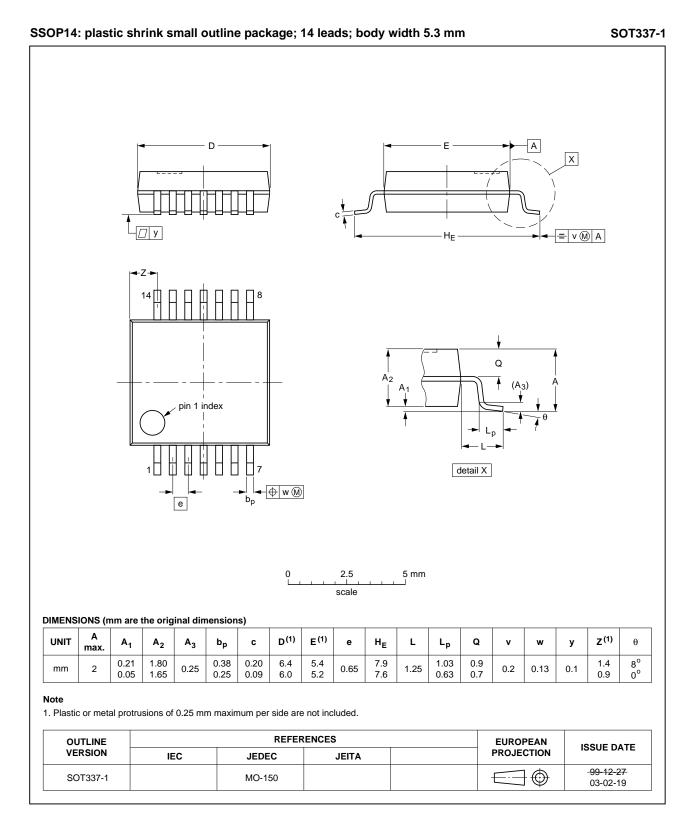
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#### SO14: plastic small outline package; 14 leads; body width 3.9 mm

#### Fig 10. Package outline SOT108-1 (SO14)

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#### Fig 11. Package outline SOT337-1 (SSOP14)

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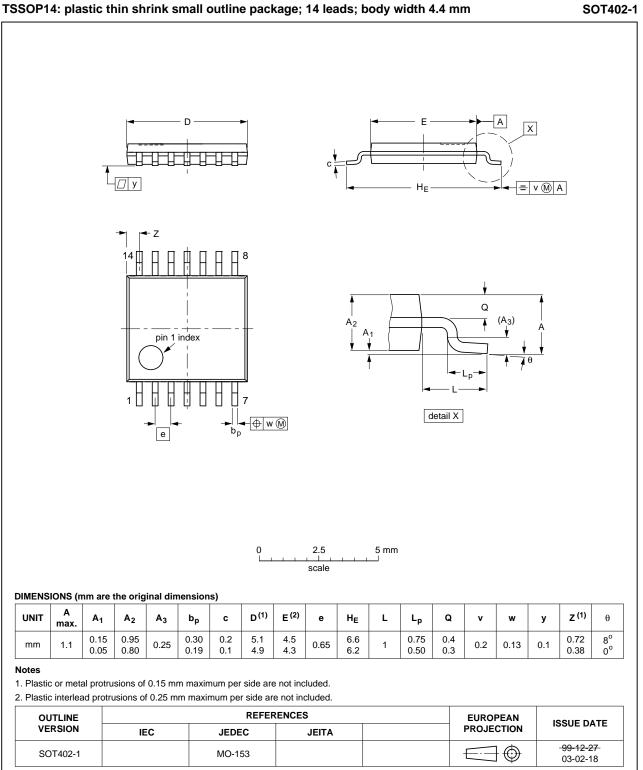
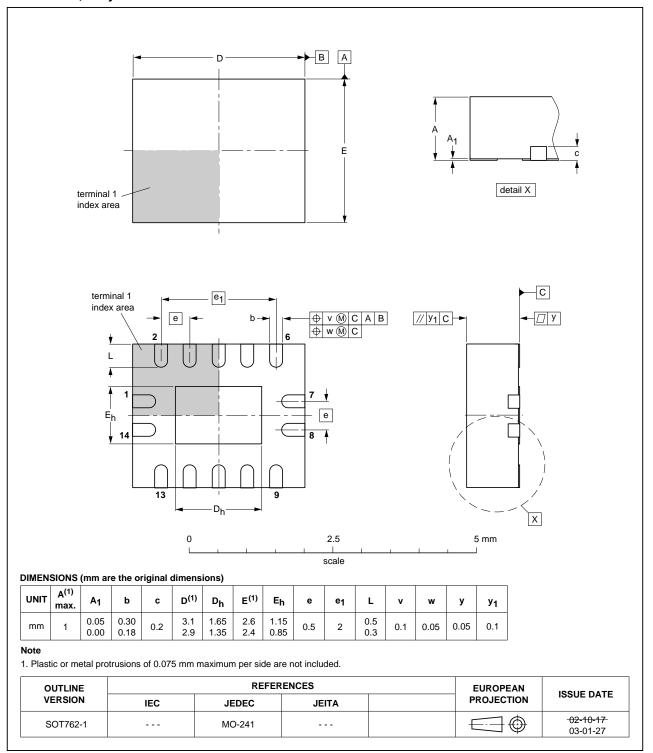


Fig 12. Package outline SOT402-1 (TSSOP14)



DHVQFN14: plastic dual in-line compatible thermal enhanced very thin quad flat package; no leads; 14 terminals; body 2.5 x 3 x 0.85 mm SOT762-1

#### Fig 13. Package outline SOT762-1 (DHVQFN14)

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Quad buffer; 3-state

### **13. Abbreviations**

Table 9. Abb	eviations
Acronym	Description
BiCMOS	BipolarCMOS
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model

### 14. Revision history

#### Table 10. Revision history **Document ID Release date** Data sheet status Change notice Supersedes Product data sheet 74ABT125 v.6 20111103 74ABT125 v.5 -Modifications: • Legal pages updated 74ABT125 v.5 20101124 Product data sheet 74ABT125 v.4 \_ 74ABT125 v.4 20100427 Product data sheet 74ABT125 v.3 \_ 74ABT125 v.3 20080429 Product data sheet -74ABT125 v.2 Product specification 74ABT125 v.2 19980116 74ABT125 v.1 -74ABT125 v.1 19960305 \_ \_ \_

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